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Front Matter: Volume 9491

, "Front Matter: Volume 9491," Proc. SPIE 9491, Sensors for Extreme Harsh Environments II, 949101 (28 May 2015); doi: 10.1117/12.2199541

SPIE.

Event: SPIE Sensing Technology + Applications, 2015, Baltimore, MD, United States

PROCEEDINGS OF SPIE

Sensors for Extreme Harsh Environments II

Debbie G. Senesky
Sachin Dekate
Editors

22–23 April 2015
Baltimore, Maryland, United States

Sponsored and Published by
SPIE

Volume 9491

Proceedings of SPIE 0277-786X, V. 9491

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

Sensors for Extreme Harsh Environments II, edited by Debbie G. Senesky, Sachin Dekate, Proc. of SPIE
Vol. 9491, 949101 · © 2015 SPIE · CCC code: 0277-786X/15/\$18 · doi: 10.1117/12.2199541

Proc. of SPIE Vol. 9491 949101-1

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Author(s), "Title of Paper," in *Sensors for Extreme Harsh Environments II*, edited by Debbie G. Senesky, Sachin Dekate, Proceedings of SPIE Vol. 9491 (SPIE, Bellingham, WA, 2015) Article CID Number.

ISSN: 0277-786X

ISBN: 9781628416077

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time) · Fax +1 360 647 1445

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